



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				Application Number	Not yet assigned
				Filing Date	February 17, 2004
				First Named Inventor	Rajski
				Art Unit	--
				Examiner Name	--
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Examiner's Initials*	Cite No. (optional)	Number	Date	Name	
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		3,700,869	Oct-72	Low et al.	
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		5,173,906	Dec-92	Dreibelbis et al.	
<i>JA</i>		5,268,949	Dec-93	Watanabe	

EXAMINER SIGNATURE: <i>D. H. Malzahn</i>	DATE CONSIDERED: <i>3/21/05</i>
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D. H. Malczuk

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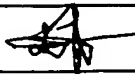
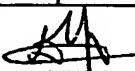
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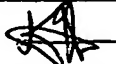
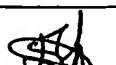

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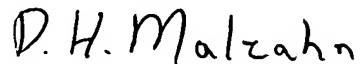
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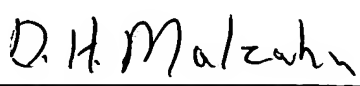
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

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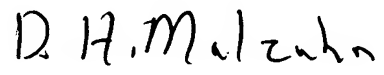
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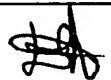

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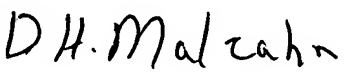
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Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS	
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**INFORMATION DISCLOSURE STATEMENT
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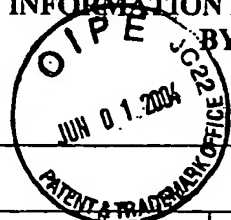
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<i>DA</i>		6,041,429	3.21.2000	Koenemann

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Examiner's Initials*	Cite No. (optional)	
		Zacharia et al., "Two-Dimensional Test Data Decompressor for Multiple Scan Designs," <i>International Test Conference</i> , pp. 186-194 (1996).

EXAMINER
SIGNATURE:

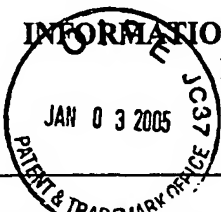
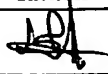

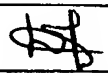



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



DATE


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3/22/05

* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT 		Attorney Docket Number	1011-67627-01		
		Application Number	10/781,031		
		Filing Date	February 17, 2004		
		First Named Inventor	Rajski		
		Art Unit	2124		
		Examiner Name			
U.S. PATENT DOCUMENTS					
NOTE: If the application was filed after June 30, 2003, copies of United States patents and United States published patent applications do not have to be provided to the Patent Office. This requirement of 37 C.F.R. § 1.98(a)(2)(i) has been waived by the United States Patent and Trademark Office pursuant to the Official Gazette Notice on August 5, 2003 (1276 OG 55).					
Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee	
		4,536,881	8.20.1985	Kasuya	
		5,202,889	4.13.1993	Aharon et al.	
		5,701,308	12.23.1997	Attaway et al.	
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		6,829,740	12.7.2004	Rajski et al.	
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Examiner's Initials*	Cite No. (optional)	Number	Filing Date	Name of Applicant	
		09/620,021	7.21.2000	Rajski et al.	
FOREIGN PATENT DOCUMENTS					
Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee
		Europe	EP 0372226	6.13.1990	Bardell
		Europe	EP 0438322	7.24.1991	Murase
		Europe	EP 0481097	4.22.1992	Diebold et al.
EXAMINER SIGNATURE: <i>D. H. Mulzahn</i>			DATE CONSIDERED: <i>3/22/05</i>		
* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.					

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FOREIGN PATENT DOCUMENTS					
Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee
		Japan	JP 4-236378	8.25.1992	Diebold et al.
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		Europe	EP 0887930	12.30.1998	Tarrab et al.
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Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS			
		Bassett et al., "Low-Cost Testing of High-Density Logic Components," <i>IEEE Design & Test of Computers</i> , pp. 15-28 (April 1990).			
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		Wang, "BIST Using Pseudorandom Test Vectors and Signature Analysis," <i>IEEE Custom Integrated Circuits Conference</i> , pp. 1611-1618 (1998).			

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